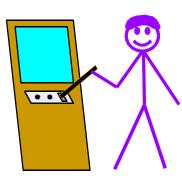


Cl'ement gave me a lot of help, ideas, advice. We first started talking about the problem due to a cstheory.stackexchange.com post.

Drawing Conclusions from Data



Given i.i.d. samples from a discrete distribution A, what can you tell me about A?

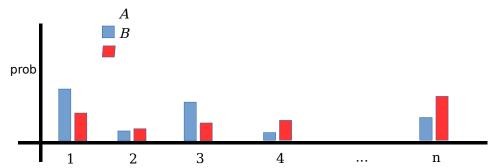
This paper:

- **Learning:** Estimate *A* "accurately"
- Uniformity Testing: Is A uniform or "far from" uniform?

Previously studied: ℓ_1 distance

(equivalently: total variation distance):

$$||A-B||_1 = \sum_{i=1}^n |A_i - B_i|$$



This work:
$$\ell_p$$
 distance, $p \ge 1$

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

$$||A-B||_{\infty} = \max_{i=1...n} |A_i - B_i|$$

$$A$$
prob
$$1$$

$$2$$

$$3$$

$$4$$
...
$$1$$

This paper considers the same questions for general lp metrics. The functional form isn't important, main point is that:

- defined for all real p >= 1
- I1 is Manhattan distance
- 12 is Euclidean distance
- as we increase p, we put more emphasis on few "heavy" elements
- extreme case is linfinity which only measures largest difference

This work: ℓ_p distance, $p \ge 1$

$$||A-B||_{p} = \left(\sum_{i=1}^{n} |A_{i} - B_{i}|^{p}\right)^{\frac{1}{p}}$$

$$||A-B||_{\infty} = \max_{i=1, n} |A_{i} - B_{i}|$$

Given n, ϵ :

Learning: Output \hat{A} such that $\|\hat{A} - A\|_p \le \epsilon$.

Uniformity testing: If A=U, output "unif"; if $\|A-U\|_p \ge \epsilon$, "not".

Both cases: Except with constant failure probability δ (e.g. 1/3)

Results

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$



- Upper and lower bounds for each ℓ_p metric.
- Matching up to constant factors in most cases.

Unlike ℓ_1 case:

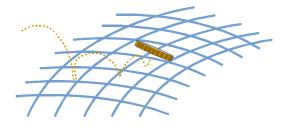
- Exists a sufficient # of samples independent of n
- Behavior differs in "small" and "large" *n* regimes

Why care about ℓ_p ? $\|A-B\|_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

Why Bo cares:

- I like the math/probability involved
- Fundamental problems deserve elegant algorithms/proofs (and small constants)

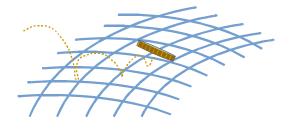


Why care about ℓ_p ? $||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

Why else you might care:

- Small data in a big world. What if we do not have enough samples to draw confident ℓ_1 conclusions?
- ℓ_p testers/learners are often useful as subroutines (Batu et al 2013, Diakonikolas et al 2015, ...)



8

It will turn out that we can often draw lp conclusions with far fewer samples, especially over large distributions.

What was known?

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

- **Learning**: order-optimal ℓ_1 (folklore), $O\left(\frac{n}{\epsilon^2}\right)$ also ℓ_2 and ℓ_∞ .
- Uniformity testing:

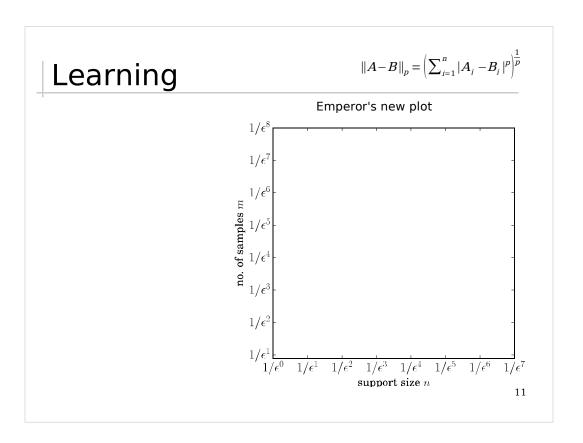
$$O\left(\frac{\sqrt{n}}{\epsilon^2}\right)$$

- ℓ_1 : order-optimal lower, and upper for "very big" n (Paninski 2008)
- Independently (Diakonikolas, Kane, Nikishkin 2015): order-optimal ℓ_1 , and ℓ_2 for small-n regime
- Note: many cases "immediate" from prior work, most (all?) cases probably "easy" to experts
- But hopefully when taken together, big picture insights emerge

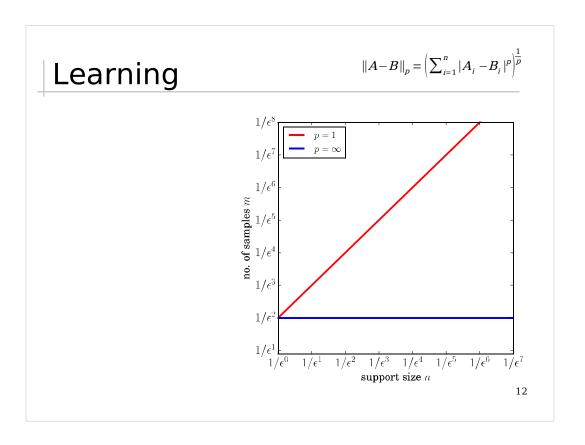
Outline

- Introductory stuff ✓
- Learning
- Uniformity testing
- Summary

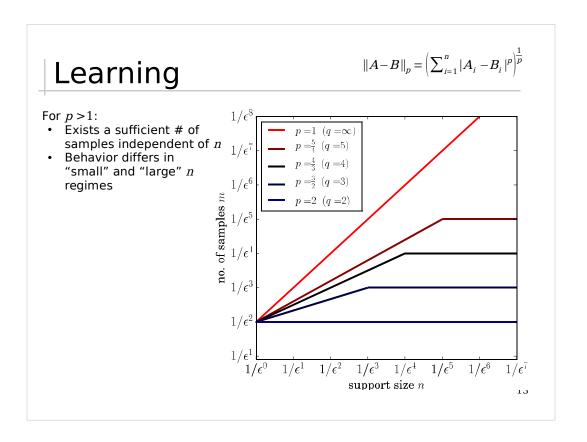




Think of the epsilon tolerance as 0.01 or something. Now we'll think about support size n in terms of powers of 1/epsilon. The question is how many samples we need as n changes. Note the plot is in log-log scale.



Starting point: known bounds look like this.



Here's what bounds look like for learning, necessary and sufficient up to constant factors, for 5 particular choices of lp metric. Note lp for $2 \le p \le infinity$ is always $1/eps^2$ samples.

In between 1 and 2, we have a small-n regime where the sample complexity increases, then a large-n regime where it's constant. Before we see what the bounds are, let's see the algorithm.

Learning Alg

$$||A - B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

1. Let $Pr[i] \propto \#$ samples of i

Learning Alg

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

1. Let $Pr[i] \propto \#$ samples of i

Analysis:

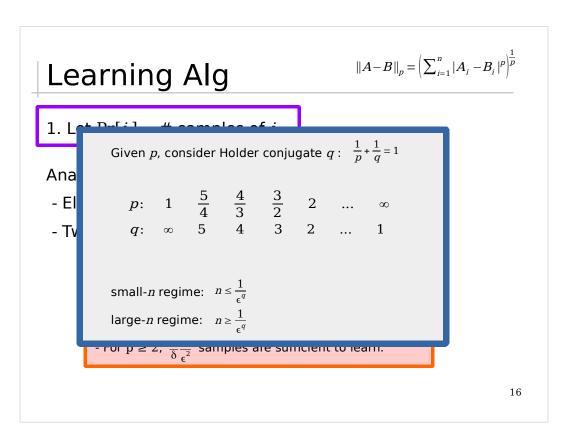
- Elegant "folklore" proof for ℓ₂ (thanks Clément!)
- Clément and I extended to general ℓ_p and large-n cases

Theorem (in particular):

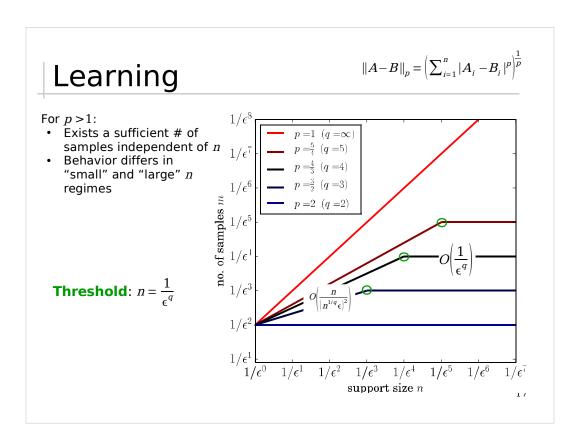
- For p = 1, $\frac{1}{\delta}\frac{n}{\epsilon^2}$ samples are sufficient to learn. For p \geq 2, $\frac{1}{\delta}\frac{1}{\epsilon^2}$ samples are sufficient to learn.

15

There's no big-O in the theorem – the constant is 1!



It turns out the conjugate pairs, as in analysis, become important. For p > 1, a key threshold is $1/eps^q$.



In general, for the small-n regime we have the bound shown (exact form not important for this talk), and for the large-n regime the bound is 1/eps^q, which is interesting because the "threshold" for large-n is 1/eps^q.

Outline

- Introductory stuff ✓
- Learning ✓
- Uniformity testing
- Summary

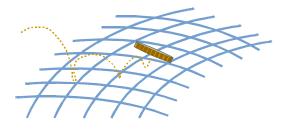


Classic Coin Question

Coin: either fair or one side with $\boldsymbol{\varepsilon}$ more probability.

Q: How many flips to tell?

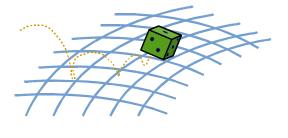
A: $O\left(\frac{1}{\epsilon^2}\right)$.



Classic Dice Question?

6-sided die: either fair or one side with ε more probability.

Q: Do we need more trials than the coin, or fewer?



20

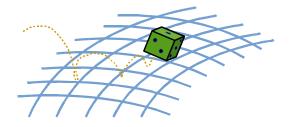
I don't know of anyone who asked this question before.

Classic Dice Question?

6-sided die: either fair or one side with ε more probability.

Q: Do we need more trials than the coin, or fewer?

A: Fewer!



Intuition: With 2-sided coin, large variance in the counts of heads and tails. Need more flips for the bias to "overwhelm" the variance.

With 6-sided die, each side has smaller variance.

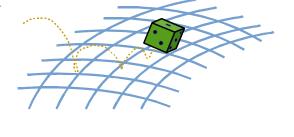
Classic Dice Question?

6-sided die: either fair or one side with ε more probability.

Q: Do we need more trials than the coin, or fewer?

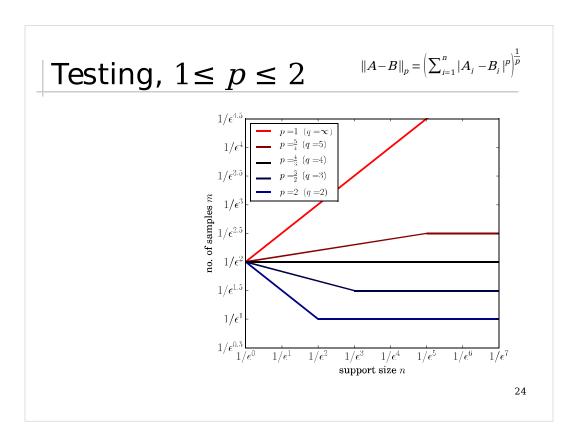
A: Fewer! (ℓ_{∞})

For ℓ_1 , need *more*. In between?



23

That was an l-infinity question since we had one outlier coordinate. On the other hand, for l-1 problems we need more samples.



For lp uniformity testing with p=4/3, for every support size n, theta(1/eps^2) samples is necessary and sufficient (whether you have a coin, or a die, or a lottery, or whatever). For p < 4/3, increasing in n in small-n regime, then constant. For p > 4/3, decreasing then constant.

Testing Alg

 $||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$

Collision: pair of samples that are both of the same coordinate

Prior work counting collisions: Paninski (2008) (sort of); Goldreich and Don (2000); Batu, Fortnow, Rubinfeld, and Smith (2005)

25

Not the expected number of collisions when drawing m samples from A is

(m choose 2) ||A||_2^2

- = $(m \text{ choose } 2) (||U||_2^2 + ||A-U||_2^2)$
- = (m choose 2) ($1/n + ||A-U||_2^2$).
- So the I2 distance to uniformity directly controls the expected number of samples.

Testing Alg

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

- 1. Let C = # collisions
- 2. Pick threshold T
- 3. If $C \le T$, output "uniform"; else, "not".

Alg is optimal for all $1 \le p \le 2$, all regimes! (by selecting # samples and T appropriately)

26

Point: uniform distribution minimizes number of collisions.

Testing Alg

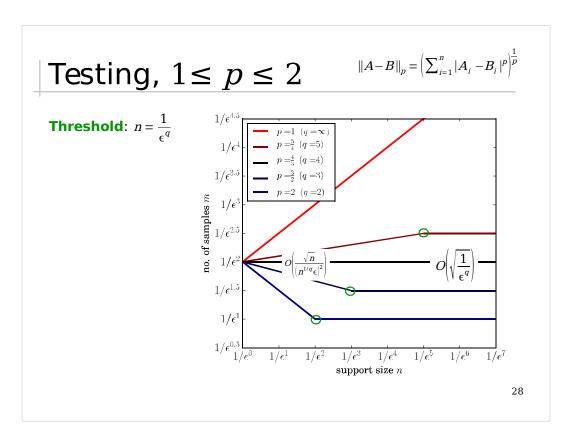
$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

- 1. Let C = # collisions
- 2. Pick threshold T
- 3. If $C \le T$, output "uniform"; else, "not".

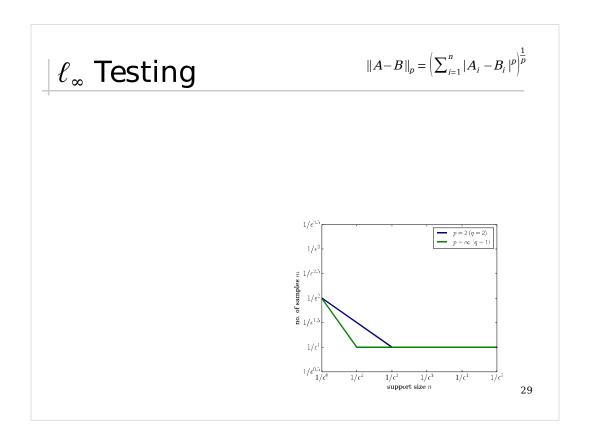
Alg is optimal for all $1 \le p \le 2$, all regimes! (by selecting # samples and T appropriately)

Theorem (in particular):

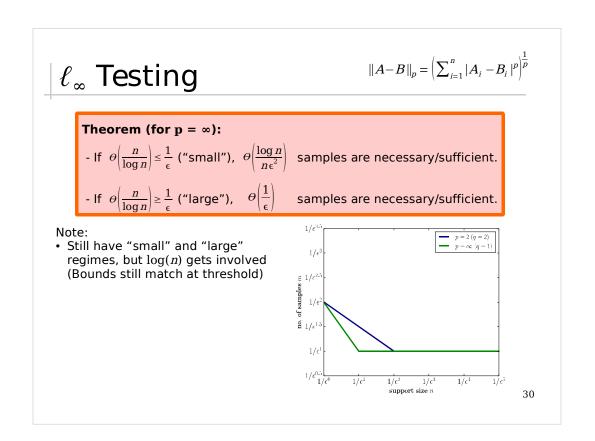
- For p = 1, $\frac{9}{\delta}\frac{\sqrt{n}}{\varepsilon^2}$ samples are sufficient to test uniformity.
- For p = 2, $\max \frac{9}{\delta} \frac{1}{\sqrt{n}\epsilon^2}$, $\frac{9}{\delta} \frac{1}{\epsilon}$ samples suffice.



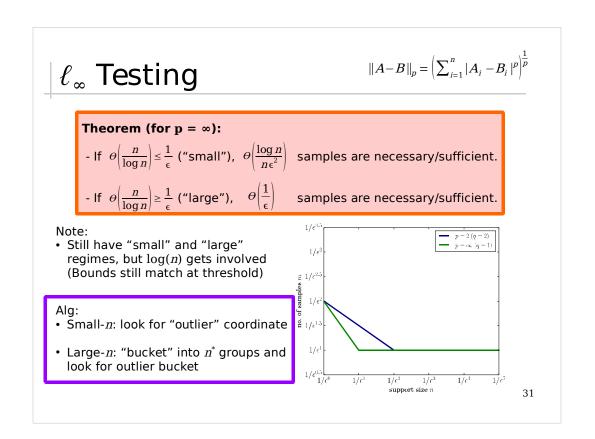
For small-n regime, bound isn't so important.
For large-n regime, it is sqrt(1/eps^q), interesting because n=1/eps^q is the threshold.



The blue line is the sample complexity for I2 testing; green is linfinity. So it decreases more sharply and is then constant at 1/epsilon.

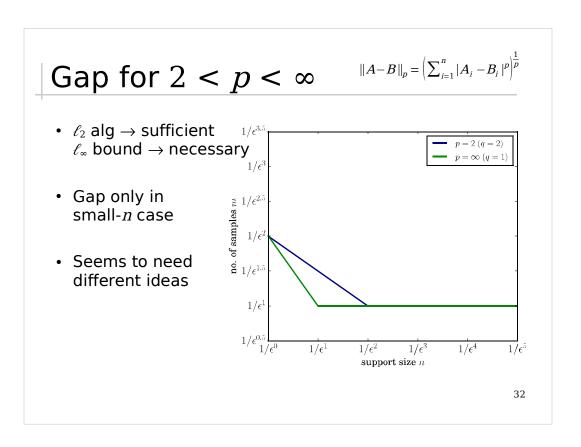


Actually I'm quite happy to have worked this out cleanly (tight everywhere to constant factors). Note that at the threshold between large and small n, the bounds match.



Here, n^* is the "threshold" n, the value where Theta($n^*/log(n^*)$) = 1/epsilon. So when n is large, no matter how large it is, group the coordinates into n^* groups and pretend it's the uniform distribution on support n^* .

The proof here is just chernoff bound on each coordinate (or bucket) and union-bound over the coordinates (buckets). The cool thing is it's tight to constant factors.



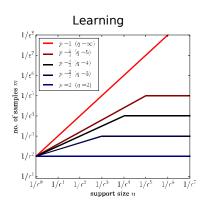
Outline

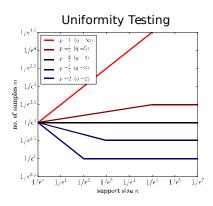
- Introductory stuff ✓
- Learning ✓
- Uniformity testing ✓
- Summary



Algorithms Summary

- Learning: naive alg is order-optimal everywhere
- **Uniformity testing**: Collision Tester is order-optimal for $1 \le p \le 2$
- Uniformity testing for ℓ_∞ : "almost-naive" alg is order-optimal

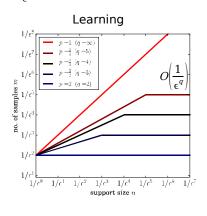


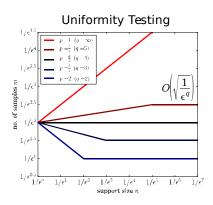


Ideas Summary

For p > 1:

- Exists a sufficient # of samples independent of n
- Behavior differs in "small" and "large" n regimes
- $\frac{1}{\epsilon^q}$ seems to upper-bound "apparent support size"

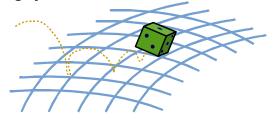




Future Work

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

- Close gap for uniformity testing, 2 , small <math>n
- Strengthen "tightness" of lower bound for small-n learning, $1 \le p < 2$
- Test and learn "thin" distributions?
- Test and learn when *n* is not known?
- Test and learn for other "exotic" metrics? (Do Ba, Nguyen, Nguyen, Rubinfeld 2011)



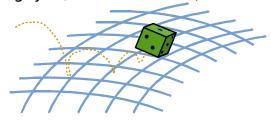
36

By "thin", I mean small I-infty norm (every coordinate has small probability). Should definitely be easier to e.g. learn thin distributions for at least some Ip metrics.

Future Work

$$||A-B||_p = \left(\sum_{i=1}^n |A_i - B_i|^p\right)^{\frac{1}{p}}$$

- Close gap for uniformity testing, 2 , small <math>n
- Strengthen "tightness" of lower bound for small-n learning, $1 \le p < 2$
- Test and learn "thin" distributions?
- Test and learn when *n* is not known?
- Test and learn for other "exotic" metrics? (Do Ba, Nguyen, Nguyen, Rubinfeld 2011)



Thanks!